



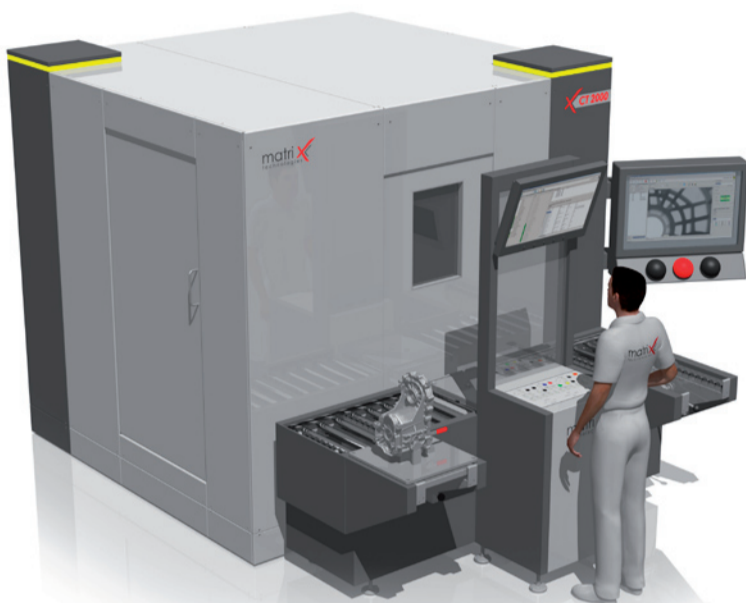
Qualify with us

Control Stuttgart

Hall 1, Booth 1502

(Fraunhofer Gesellschaft)

New automatic X-ray systems for material analyzing

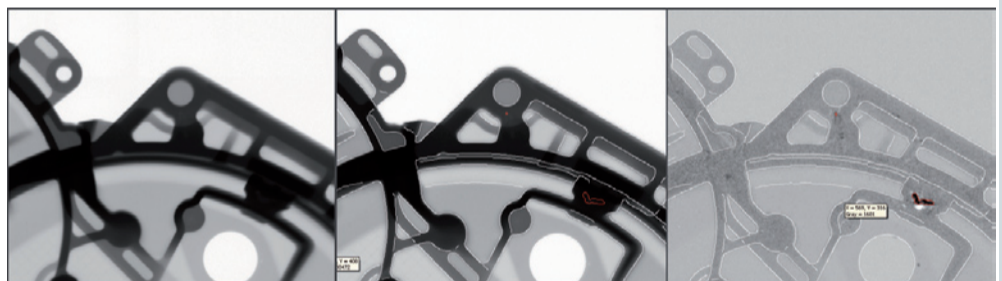

CT-2000
Automatic X-Ray inspection with combined CT


X-RAY system for advanced material analyzing with high precision C-arm technology for automatic transmission X-ray and CT reconstruction

- flexible sample types by multi-axes motion technique with C-arm setup for X-Ray source and digital X-Eye detector (Fraunhofer) for superb X-Ray image quality
- new digital **X-Eye technology** guaranties first time a digital detector performance with no image lags and minimized pixel-defects!
- latest Fraunhofer CT-technology with best in class Fraunhofer **Volex-CT** and with the new **HeliX-CT** Option for "artefact-free" reconstruction
- fully automatic defect detection including defect-size and depth for voids (<1mm), porosities, oxyds, cracks, ...


ISAR (intelligent system for automatic radiology)

Automatic image processing software for a wide range of NDT applications - based on the well established Fraunhofer reference image technique for high performance material analyzes down to 1% defect-detection capability in relation to the material thickness


Matrix Inspection and Process Software (MIPS)


The MIPS_NDT inspection platform is specifically designed for fully automatic material analyzing under In-line production conditions. The new intelligent difference image technique **MIPS_ARA** (Advanced Referential Analysing technique) is eliminating the programming efforts by using a new high precise automatic registration technique (optical flow).

- Automatic high speed X-Ray analyzing capability for 100% inspection of: castings, med. Implants, airbag-inflators, ...
- New fully automatic registration process with **ARA** referential and analyzing technique
- Object **contour-filtering** for ease-to-use defect navigation
- Combined reference-free and referential inspection capability for inhomogeneous structures

Verifikations-Station/MIPS_Verify

Verification module for X-Ray and optical systems with defect image display and graphical defect navigation

Process and status management for multiple inspection points

Reference image and failure-report management via data base

Real-Time SPC-Software/MIPS_SPC/RT

Real-time process control under production conditions with yield display and graphical defect distribution

WEB-SPC Tool / MIPS_SPC / Web

Statistic tool with web-interface for specified time frames and product seletions

On-line process control capability for every PC station via internet

Come and join the innovations!

www.m-xt.com